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LIST QF REFERENCES CITED BY APPLI	FIRST NAMED INVENTOR Yuichi ARITA et al.	-
(Use several sheets if necessary)	FILING DATE GROUP ART February 25, 2000 2763	UNIT

## **U.S. PATENT DOCUMENTS**

*EXAMINER INITIAL		DOCUMENT NO.	DATE	NAME	CLASS	SUB- CLASS	FILING DATE
	AA						
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## FOREIGN PATENT DOCUMENTS

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB- CLASS	TRANSLATION YES	NO NO
\$	АН	10003552-A	1/6/98	JAPAN			ABST only	
8	Al	10187774 A	7/21/98	JAPAN			ABST only	
	AJ							
	AL							
	АМ							
	AN							
	AO							

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

8	АМ	Copy of original Office Action issued from the Japanese Patent Office. English translation of the Office Action.
S	AN	"Catch Up Try & Check" Viewer [3D View V3.0] Low Cost and Full Functions", NIKKEI DIGITAL ENGINEERING, February, 1999, pp. 20-21. Partial English translation.
8	AO	"Catch Up Try & Check" Viewer [CALSVIEW V3.0J] "Easy finding of cross-sectional form or angle distance", NIKKEI DIGITAL ENGINEERING, July, 1998, pp. 38-39. Partial English translation.
	AP	

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		03/08/2006
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<sup>\*</sup>EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and Ref Whatere & Halen below of this form with next communication to applicant.